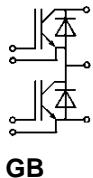


Absolute Maximum Ratings		Values	Units
Symbol	Conditions¹⁾		
V _{CES}		1200	V
V _{CGR}	R _{GE} = 20 kΩ	1200	V
I _c	T _{case} = 25/80 °C	400 / 330	A
I _{CM}	T _{case} = 25/80 °C; t _p = 1 ms	800 / 660	A
V _{GES}		± 20	V
P _{tot}	per IGBT, T _{case} = 25 °C	2500	W
T _j , (T _{stg})		- 40 . . . +150 (125)	°C
V _{isol}	AC, 1 min.	2 500 ⁷⁾	V
humidity climate	DIN 40 040	Class F	
	DIN IEC 68 T.1	40/125/56	
Inverse Diode			
I _F = - I _c	T _{case} = 25/80 °C	390 / 260	A
I _{FM} = - I _{CM}	T _{case} = 25/80 °C; t _p = 1 ms	800 / 660	A
I _{FSM}	t _p = 10 ms; sin.; T _j = 150 °C	2900	A
I _t ²	t _p = 10 ms; T _j = 150 °C	42000	A ² s

**SEMITRANS® M
IGBT Modules****SKM 400 GB 123 D****SEMITRANS 3****GB****Features**

- MOS input (voltage controlled)
- N channel, Homogeneous Si
- Low inductance case
- Very low tail current with low temperature dependence
- High short circuit capability, self limiting to 6 * I_{cnom}
- Latch-up free
- Fast & soft inverse CAL diodes⁸⁾
- Isolated copper baseplate using DCB Direct Copper Bonding Technology
- Large clearance (12 mm) and creepage distances (20 mm).

Characteristics	Conditions¹⁾	min.	typ.	max.	Units
V _{(BR)CES}	V _{GE} = 0, I _c = 4 mA	≥ V _{CES}	-	-	V
V _{GE(th)}	V _{GE} = V _{CE} , I _c = 12 mA	4,5	5,5	6,5	V
I _{CES}	V _{GE} = 0 { T _j = 25 °C	-	0,4	6	mA
	V _{CE} = V _{CES} } T _j = 125 °C	-	24	-	mA
I _{GES}	V _{GE} = 20 V, V _{CE} = 0	-	-	1	μA
V _{CEsat}	I _c = 300 A } V _{GE} = 15 V;	-	2,5(3,1)	3(3,7)	V
V _{CEsat}	I _c = 400 A } T _j = 25 (125) °C	-	2,8(3,6)	-	V
g _{fs}	V _{CE} = 20 V, I _c = 300 A	124	-	-	S
C _{CHC}		-	1300	1500	pF
C _{ies}	{ V _{GE} = 0	-	22	30	nF
C _{oes}	V _{CE} = 25 V	-	3,3	4	nF
C _{res}	f = 1 MHz	-	1,2	1,6	nF
L _{CE}		-	-	20	nH
t _{d(on)}	{ V _{CC} = 600 V	-	200	400	ns
t _r	V _{GE} = +15 V/-15V ³⁾	-	115	220	ns
t _{d(off)}	I _c = 300 A, ind. load	-	720	900	ns
t _f	R _{Gon} = R _{Goff} = 3,3 Ω	-	80	100	ns
E _{on} ⁵⁾	T _j = 125 °C	-	38	-	mWs
E _{off} ⁵⁾		-	40	-	mWs
Inverse Diode ⁸⁾					
V _F = V _{EC}	I _F = 300 A { V _{GE} = 0 V;	-	2,0(1,8)	2,5	V
V _F = V _{EC}	I _F = 400 A } T _j = 25 (125) °C	-	2,25(2,05)	-	V
V _{TO}	T _j = 125 °C ²⁾	-	-	1,2	V
r _T	T _j = 125 °C ²⁾	-	2,5	3,5	mΩ
I _{IRRM}	I _F = 300 A; T _j = 25 (125) °C ²⁾	-	85(140)	-	A
Q _{rr}	I _F = 300 A; T _j = 25 (125) °C ²⁾	-	13(40)	-	μC
Thermal Characteristics					
R _{thjc}	per IGBT	-	-	0,05	°C/W
R _{thjc}	per diode D	-	-	0,125	°C/W
R _{thch}	per module	-	-	0,038	°C/W

Typical Applications: → B6-199

- Switching (not for linear use)

¹⁾ T_{case} = 25 °C, unless otherwise specified

²⁾ I_F = - I_c, V_R = 600 V,
- dI_F/dt = 2000 A/μs, V_{GE} = 0 V

³⁾ Use V_{GEoff} = -5 ... -15 V

⁵⁾ See fig. 2 + 3; R_{Goff} = 3,3 Ω

⁷⁾ V_{isol} = 4000 V_{rms} on request

⁸⁾ CAL = Controlled Axial Lifetime Technology.

Cases and mech. data → B6-200
SEMITRANS 3

SKM 400 GB 123 D

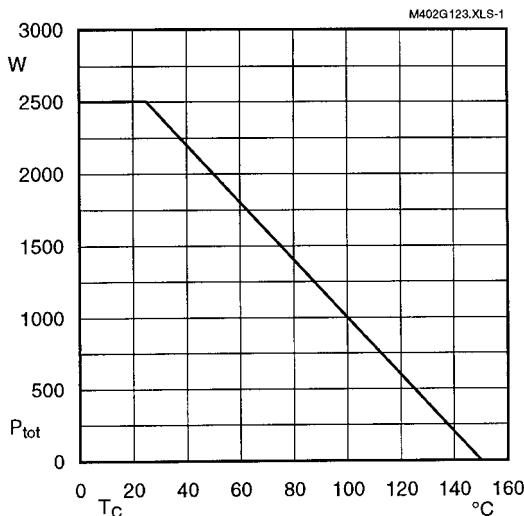


Fig. 1 Rated power dissipation $P_{tot} = f (T_C)$

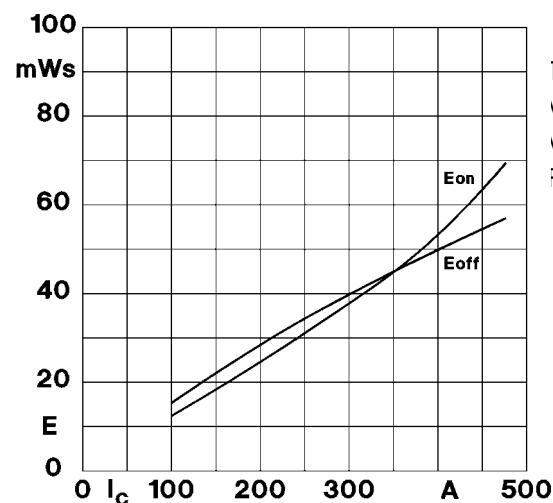


Fig. 2 Turn-on /-off energy = f (I_C)

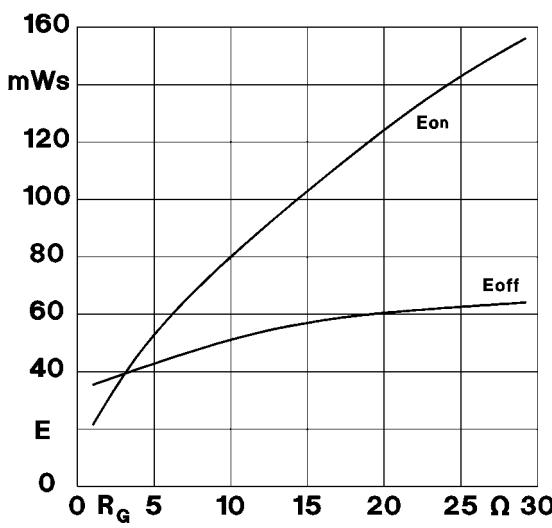


Fig. 3 Turn-on /-off energy = f (R_G)

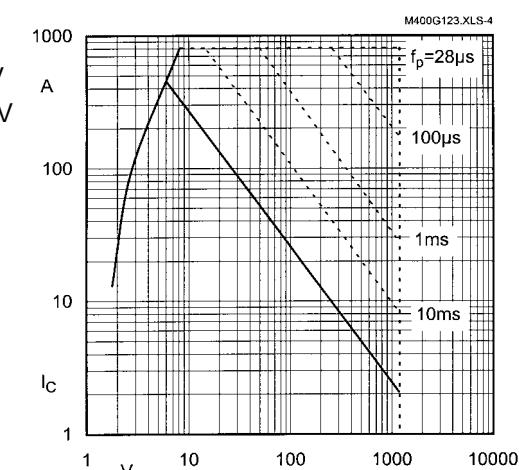


Fig. 4 Maximum safe operating area (SOA) $I_C = f (V_{CE})$

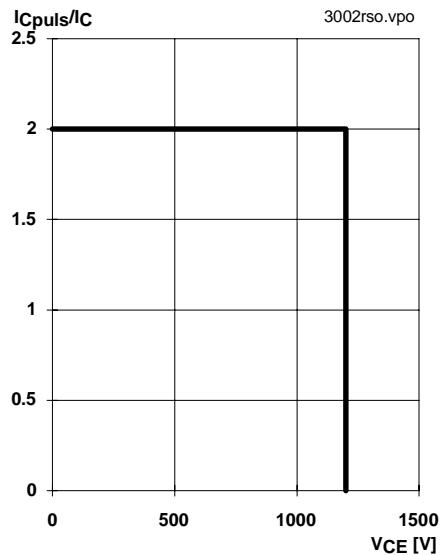


Fig. 5 Turn-off safe operating area (RBSOA)

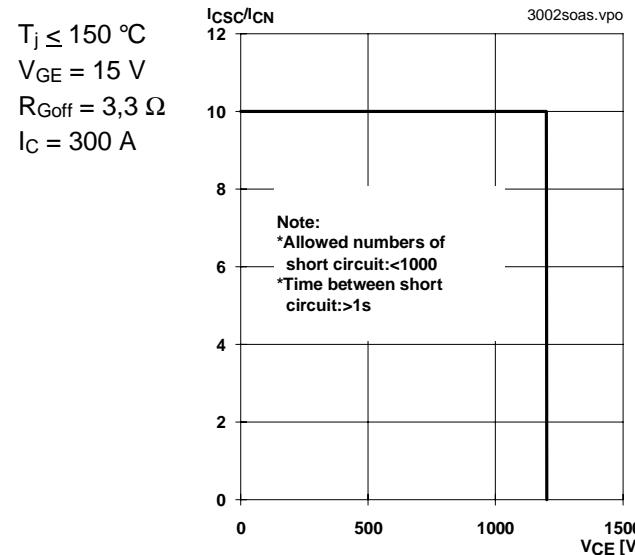
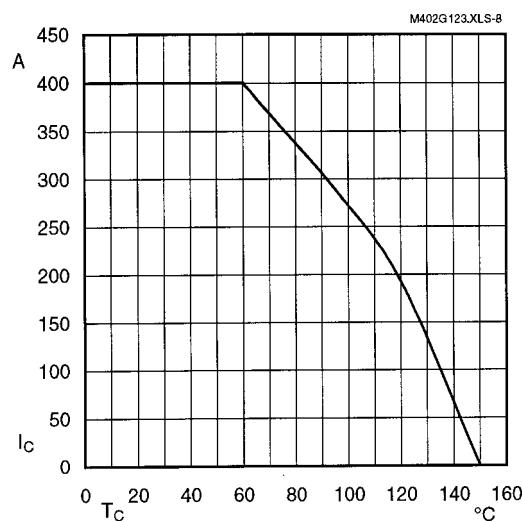


Fig. 6 Safe operating area at short circuit $I_C = f (V_{CE})$



$T_j = 150 \text{ }^\circ\text{C}$
 $V_{GE} \geq 15 \text{ V}$

Fig. 8 Rated current vs. temperature $I_C = f(T_C)$

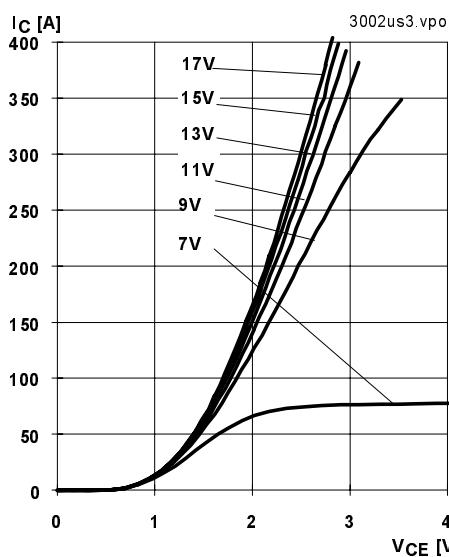


Fig. 9 Typ. output characteristic, $t_p = 80 \mu\text{s}; 25 \text{ }^\circ\text{C}$

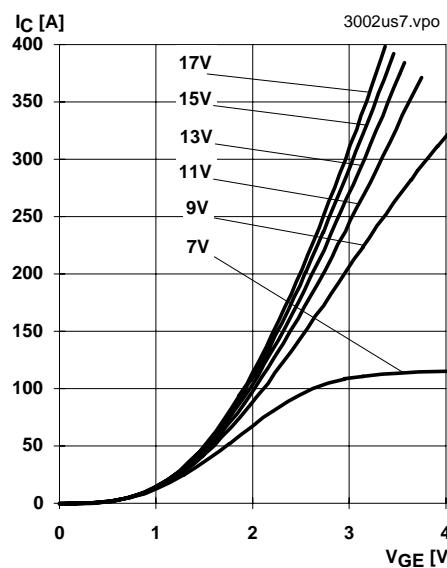


Fig. 10 Typ. output characteristic, $t_p = 80 \mu\text{s}; 125 \text{ }^\circ\text{C}$

$$P_{cond(t)} = V_{CEsat(t)} \cdot I_C(t)$$

$$V_{CEsat(t)} = V_{CE(TO)(Tj)} + r_{CE(Tj)} \cdot I_C(t)$$

$$V_{CE(TO)(Tj)} \leq 1,5 + 0,002 (T_j - 25) \text{ [V]}$$

$$\text{typ.: } r_{CE(Tj)} = 0,0033 + 0,000014 (T_j - 25) \text{ [\Omega]}$$

$$\text{max.: } r_{CE(Tj)} = 0,0050 + 0,000017 (T_j - 25) \text{ [\Omega]}$$

$$\text{valid for } V_{GE} = +15 \text{ to } -1 \text{ [V]; } I_C > 0,3 I_{Cnom}$$

Fig. 11 Saturation characteristic (IGBT)
Calculation elements and equations

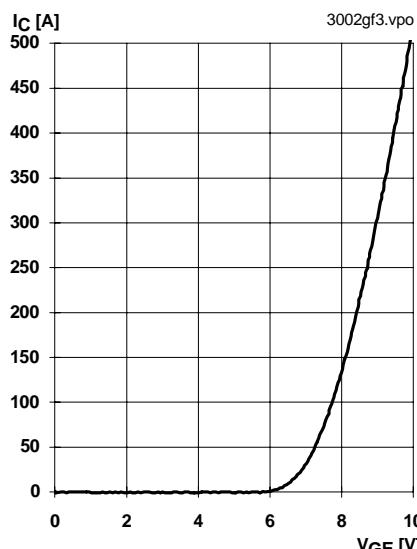


Fig. 12 Typ. transfer characteristic, $t_p = 80 \mu\text{s}; V_{CE} = 20 \text{ V}$

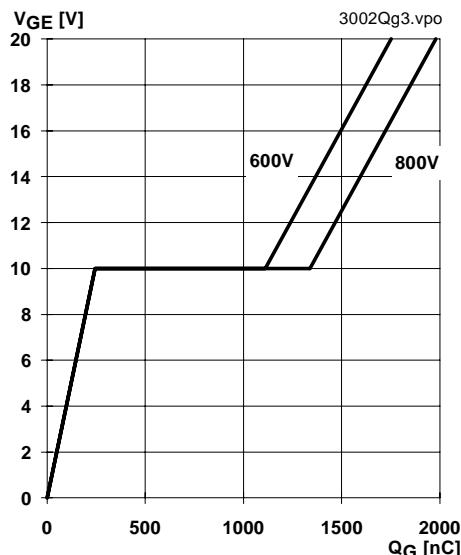


Fig. 13 Typ. gate charge characteristic

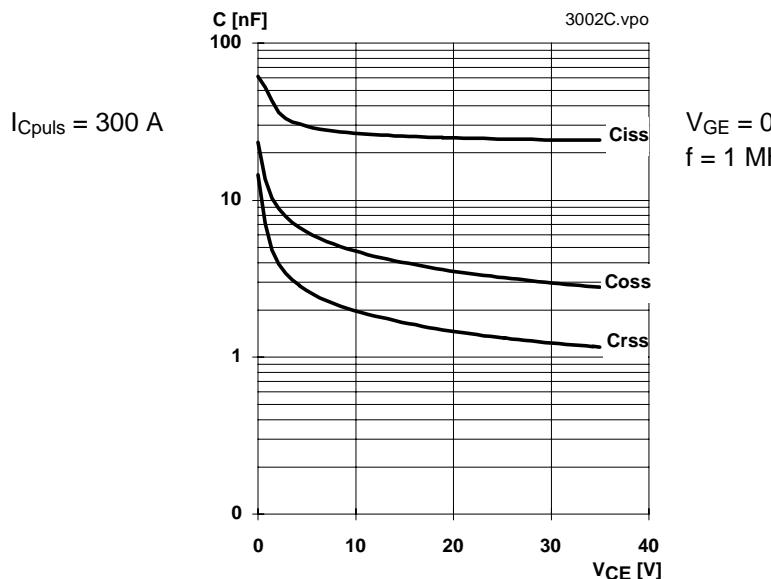


Fig. 14 Typ. capacitances vs. V_{CE}

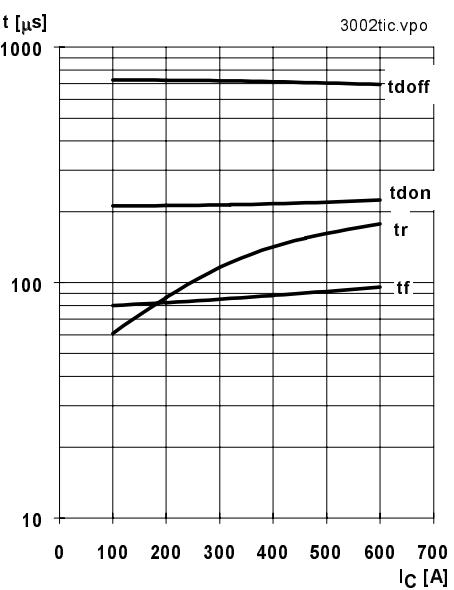


Fig. 15 Typ. switching times vs. I_C

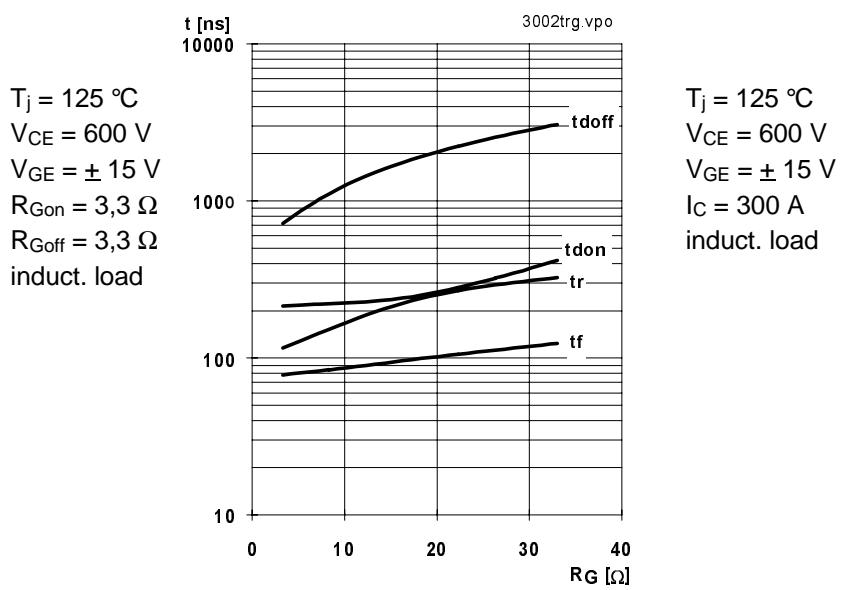


Fig. 16 Typ. switching times vs. gate resistor R_G

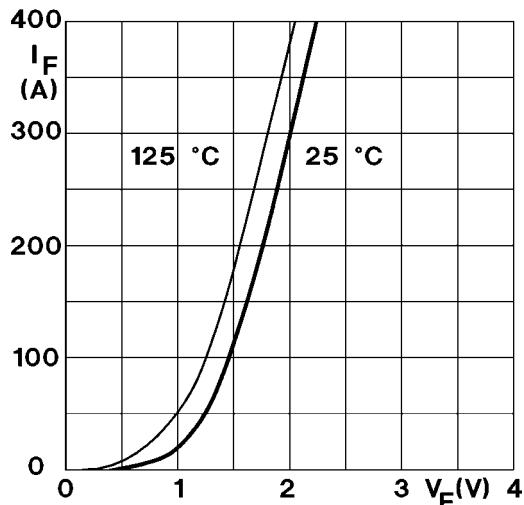


Fig. 17 Typ. CAL diode forward characteristic

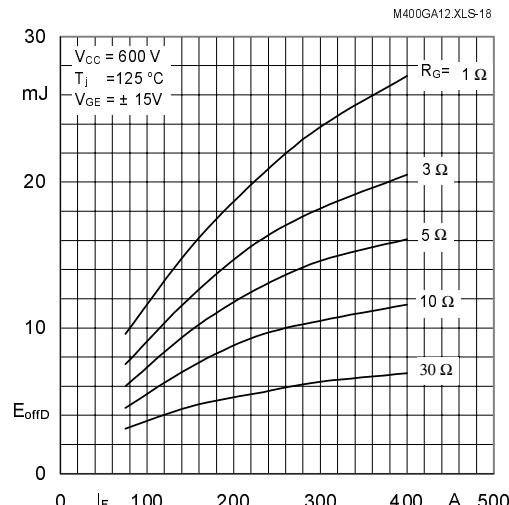


Fig. 18 Diode turn-off energy dissipation per pulse

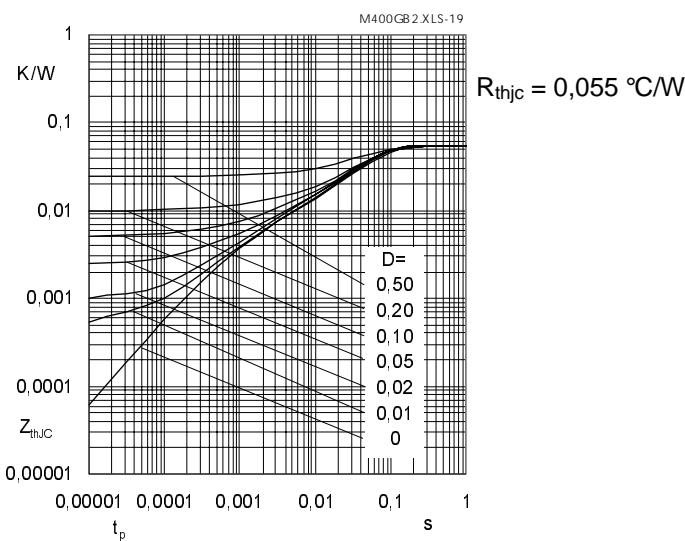


Fig. 19 Transient thermal impedance of IGBT
 $Z_{thJC} = f(t_p)$; $D = t_p / t_c = t_p \cdot f$

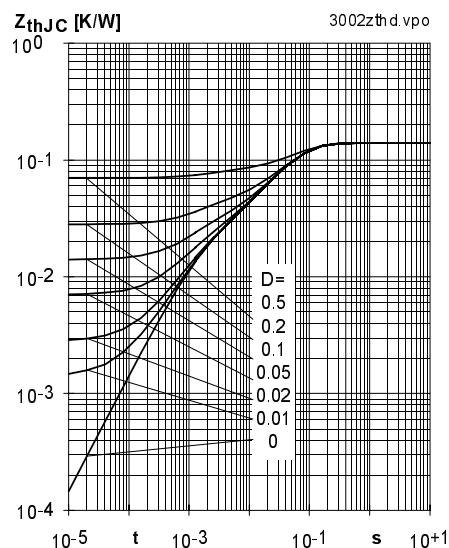


Fig. 20 Transient thermal impedance of inverse CAL diodes $Z_{thJC} = f(t_p)$; $D = t_p / t_c = t_p \cdot f$

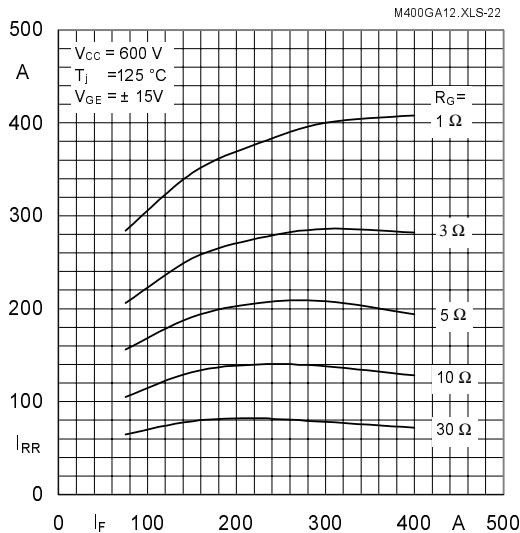


Fig. 22 Typ. CAL diode peak reverse recovery current $I_{RR} = f(I_F; R_G)$

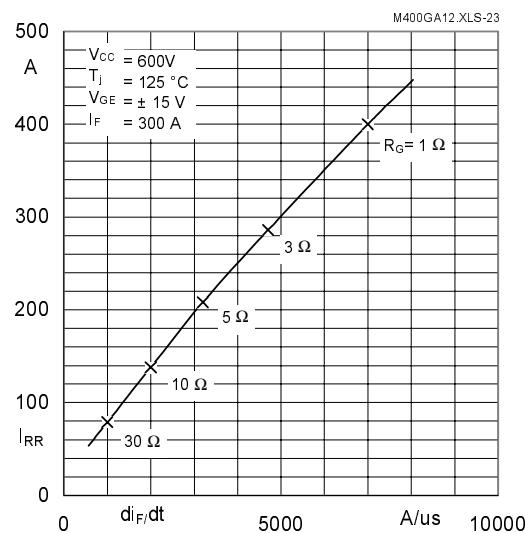


Fig. 23 Typ. CAL diode peak reverse recovery current $I_{RR} = f(di/dt)$

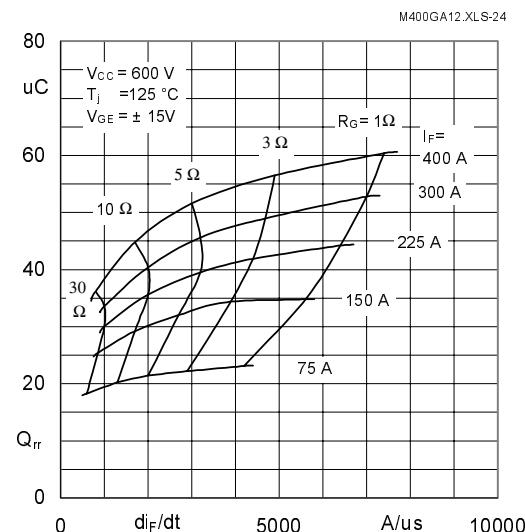


Fig. 24 Typ. CAL diode recovered charge

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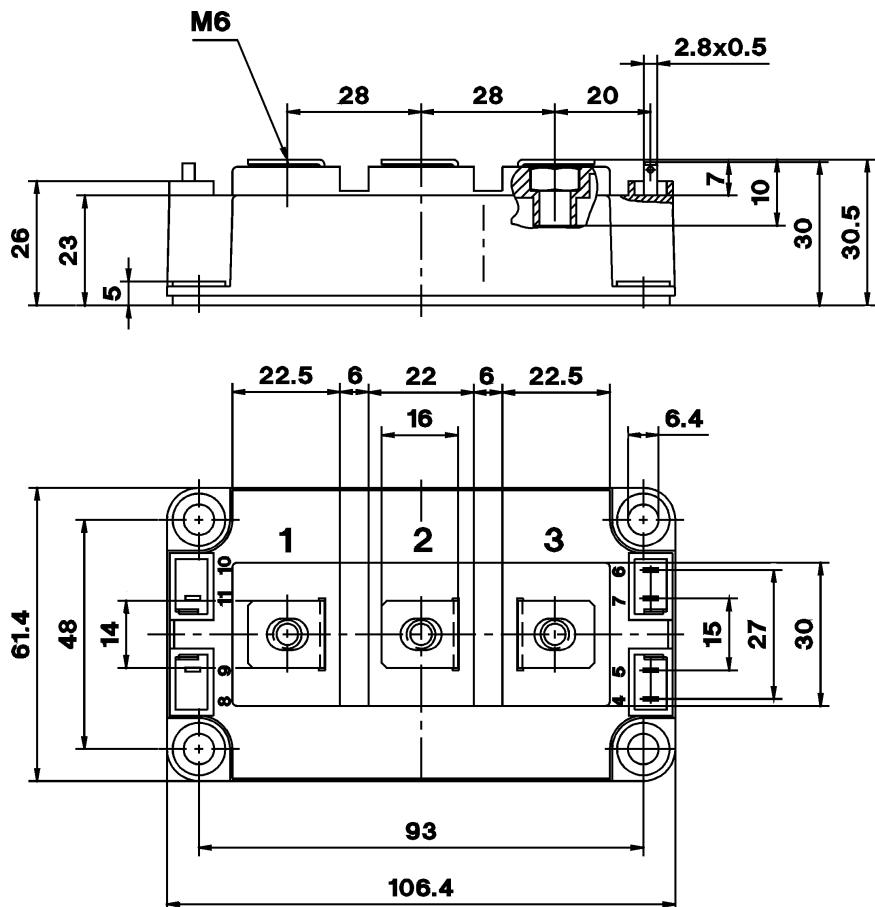
SEMITRANS 3

Case D 56

UL Recognized

File no. E 63 532

SKM 400 GB 123 D



Dimensions in mm

Case outline and circuit diagram

Symbol	Conditions		Values			Units
			min.	typ.	max.	
M ₁	to heatsink, SI Units	(M6)	3	—	5	Nm
	to heatsink, US Units		27	—	44	lb.in.
M ₂	for terminals, SI Units	(M6)	2,5	—	5	Nm
	for terminals US Units		22	—	44	lb.in.
a			—	—	5x9,81	m/s ²
w			—	—	325	g

This is an electrostatic discharge sensitive device (ESDS). Please observe the international standard IEC 747-1, Chapter IX.

Three devices are supplied in one SEMIBOX A without mounting hardware, which can be ordered separately under Ident No. 33321100 (for 10 SEMITRANS 3). Larger packing units of 12 and 20 pieces are used if suitable
Accessories → B 6 - 4.
SEMIBOX → C - 1.